



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: James M. Holden; William A. McGahan; Richard A. Yarussi; Pablo I. Rovira; and Roger R. Lowe-Webb
Assignee: Nanometrics Incorporated

Title: Apparatus and Method for the Measurement of Diffracting Structures
Serial No.: 09/670,000 Filing Date: September 25, 2000
Examiner: Chih-Cheng Glen Kao Group Art Unit: 2882
Docket No.: NAN022 US Confirmation No.: 3656

Santa Clara, California
April 7, 2006

Mail Stop RCE
Commissioner For Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO OFFICE ACTION

Dear Sir:

This Response to Office Action is responsive to the October 14, 2005, Office Action, which has a statutorily shortened period for response that ends January 14, 2006. A petition for a 3 month extension is filed herewith, giving applicants until April 14, 2006, to respond. Please enter the following amendments before taking action on the merits of the above-referenced application. This amendment is being filed with a Request for Continued Examination (RCE).

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